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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,454	IVCHENKO ET AL.	
Examiner	Art Unit	
Alan S. Chen	2182	

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SEARCH NOT (INCLUDING SEARCH	STRATEGY)
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(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT Inventor Search	1/12/2007	ASC
limited class/subclass search: 702/108-126; 710/5,8,15,62-74	1/12/2007	ASC
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